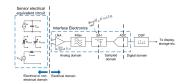
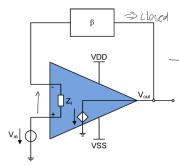
Sensor Principles

A generic sensor interface



OPAMP Basics

Opamps in feedback



Gain: $T(\omega) = \beta \cdot A_0(\omega)$ Phase Margin: $PM = 180^{\circ} + \angle (T(\omega_1)|_{|T(\omega_1)|=1})$ Gain margin:GM = $20 \cdot log_{10}(\frac{1}{T(\omega_2)})|_{\angle(T(\omega_2)=-180^{\circ})}$

Generic Transfer function

$$\begin{split} V_x &= \beta \cdot V_{\text{out}} = \\ \beta \cdot A(\omega) \cdot (V_{\text{in}} - V_x) &= \\ \beta \cdot A(\omega) \cdot (V_{\text{in}} - \beta \cdot V_{\text{out}}) \\ &= \frac{V_{\text{out}}}{V_{\text{in}}} = \frac{A(\omega)}{1 + \beta \cdot A(\omega)} \overset{A(\omega)] \gg 1}{\approx} \frac{1}{\beta} \end{split}$$

Negative Feedback and linear operation

 $A(\omega) \gg 1 \Rightarrow \text{virtual short at the}$ input $\Delta V \approx 0$ $Z_i \to \infty \Rightarrow i_{oa} \approx 0$ Voltage Drive \rightarrow negative feedback

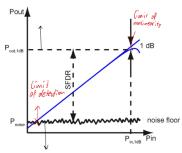
Current drive \rightarrow positive feedback

Errors and Noise

Limit of detection(LOD):

minimum measurable input amplitude $(SNR \approx 0)$

Dynamic range()DR: ratio of max and min amplitude within inaccuracy levels.



Errortypes:

Deterministic: source loading, offset, gain error

Random: thermal noise, 1/f noise Quantification:

Absolute : $\Delta x = |\hat{x} - x_0|$ Max inaccuracy:

 $\Delta x_{max} | x \in [\hat{x} - \Delta x_{max}, \hat{x} + \Delta x_{max}]$ **Error Propagation**

 $y = f(x_1, x_2, \dots, x_N)$ Deterministic fluctuations of $x_i \rightarrow$ total error: $\Delta y \approx \sum_{i=1}^{N} \frac{\partial f}{\partial x_i} \cdot \Delta x_i$

Partial derivative $\frac{\delta f}{\delta x_i}$ is called

sensitivity

Additive errors are best specified absolute and multiplicative errors are best specified relative

Interference:

Unwanted coupling of external signal

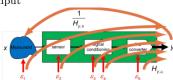
Noise: random fluctuations from $setup \rightarrow can be modeled as error$ sources

Combining Error sources

Output referred noise

Effect of an error-source on the output

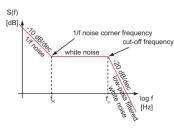
Input referred noise Equivalent effect of the error-source on the input



Find TF from ES to output $y: H_{y,ES} \Rightarrow y_{\text{out },\epsilon_2} = H_{y,\epsilon_2} \cdot \epsilon_2$ Refer result back to input wit $H_{y,x}: x_{\epsilon_2} = \frac{y_{\text{out}}, \epsilon_2}{H_{y,x}} = H_{y,\epsilon_2} \cdot \frac{\epsilon_2}{H_{y,x}}$

Lin. System noise:

 $PSD = S_y(f) = |H(f)|^2 \cdot S_x(f)$



Noise Types

Thermal noise: excitation of charge carriers(white)

Shot noise: carriers randomly crossing the barrier, dependent on DC bias and white

Flicker Noise:, due to traps in semiconduct. 1/f spectral density. MOS trans at low freq.

Thermalnoise Theorem: Every closed system at temp. T has average. Energy of $kT/2 \rightarrow$ $S_u(f) = 2kTR$ (double-sided) math $S_u(f) = 4kTR(\text{ single-sided})$ physics

Langevin Approach kt/C noise

PSD noise voltage of V_n $= S_{v_n}(f) = 4kT \cdot \Re\{Z(j2\pi f)\}$ $\rightarrow \overline{V_n^2} = kT \left[\frac{1}{C_{\infty}} - \frac{1}{C_0} \right] = \frac{kT}{C}$ **MOS IRN**

 $S_{\Delta V_{\rm nG-tot}}^{\,2} \; = 4kT \; \cdot \;$ $R_{\text{nG-tot}}$, $R_{\text{nG-tot}} = \frac{\rho}{W \cdot L \cdot f} + \frac{\gamma_{nD}}{G_m}$ with GateExcess Noise factor

 $:\gamma_{nD} = (n = 1.3) \cdot [0.5WI; 2/3SI]$ Bipolar Trans IRN:

 $S_{\Delta V_{nB}^2} = 4kT \cdot R_B$

Noise Aanalysis

small-signal-equivalent is valid. Total ORN:

 $S_{n, \text{ out }}(f) = \sum_{k=1}^{N} |H_k(f)|^2 \cdot S_{nk}(f)$ N uncorrelated NS.

 $H_k(f)$ TF from NS ton output. IRN: $S_{V_{\text{neq,IRN}}}(f) = \frac{S_{V_{\text{nout}}}(f)}{|A(f)|^2}$ with A(f) is TF

Sensor types

Information domain \rightarrow Electrical domain

Transduction: Converting a signal from the energy domain into another.

Sensors and actuators are transducers

Sources of eerror

Noise, sensitivity to unintended quantities, Noise, EMI



Tandem transducers: Multiple steps to target domain.

cross-sensitivity, sensitivity to undesired quantity

Sensor classification:

Active Sensors:

Require external source of excitation Passive / self-generating sensors:

Generate their own electrical output signal

Draws all required energy from the measurand(source loading) E: Potentiometer for angle measurements. Modulating

sensors:

Measure desired quantity by modulating

Additional source with modulated energy. Also adds error. E: Non0contact displacement measrement (rotating disk) Analog vs. Digital:

Analog: time and value continuous Digital: Discrete outputs

Deflection mode sensors:

Response to an output is a deviation from the equilibrium position

Null mode sensors:

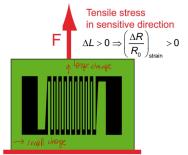
Sensor or instruments exert an influence the measured system opposing the effect of the measurand. Ideally the result is a 0 measurement, typically achieved by feedback. The opposing influence is then the sensor output. Slower than deflection, but more accurate.

Resistive sensors - strain gauges

Change in geometry under mechanical stress produces associated resistance change Volum. == const. $\rightarrow \frac{\partial V}{V_0} = \frac{L_0}{V_0} \cdot \partial A + \frac{A_0}{V_0} \cdot \partial L \wedge \frac{\partial V}{V_0} =$

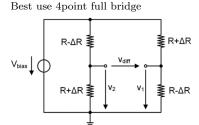
$$0 \Rightarrow \frac{\partial A}{A_0} = -\frac{\partial L}{L_0} \rightarrow \frac{\partial R}{R_0} = \frac{\partial \rho}{\rho_0} + 2\frac{\partial L}{L_0}$$
$$\rightarrow \frac{\partial R}{R_0} = \alpha \cdot \frac{\partial L}{L_0} + 2\frac{\partial L}{L_0} = \underbrace{(\alpha + 2)}_{\bullet} \cdot \frac{\partial L}{L_0}$$

k: gauge factor α proportionality factor $\frac{\partial \rho}{\rho_0} \propto \frac{\partial L}{L_0}$



Readout resistive sensors

Use a half bridge resistive divider top element sensing resistor $\frac{v_{\rm out}}{V_{\rm bias}} = \frac{R}{2R + \Delta R} \Leftrightarrow \frac{\Delta R}{R} = \frac{V_{\rm bias}}{v_{\rm out}} - 2$ Full bridge to remove offset, 2 sensing elements more sensitive. remove nonlinearity by implementing differential measurements



$$V_{\text{diff}} = v_2 - v_1 = \frac{\Delta R}{R} \cdot V_{\text{bias}}$$